

**Preliminary Amendment**

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Title: ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE TESTING AND/OR THE  
DIAGNOSTIC ANALYSIS OF AN INTEGRATED CIRCUIT

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**IN THE ABSTRACT**

Please replace the Abstract with the following rewritten paragraph:

**Abstract**

**ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE TESTING  
AND/OR THE DIAGNOSTIC ANALYSIS OF AN INTEGRATED CIRCUIT**

**Abstract**

An electrical diagnostic circuit and testing method is disclosed. In one embodiment,  
The electrical diagnostic circuit for testing an integrated circuit ~~comprises~~includes a number  
of external inputs-(E), a plurality of essentially similar, series-connected switching units and a  
circuit output-(+16). The switching units are constructed to be controllable in such a manner  
that an input signal present at the internal input of the switching unit, in dependence on a  
control signal of the switching unit, can either be forwarded unchanged to the internal input  
of the switching unit in each case arranged downstream, or can be combined with the test  
signal in each case present at the external input-(E).

~~(Figure 1)~~